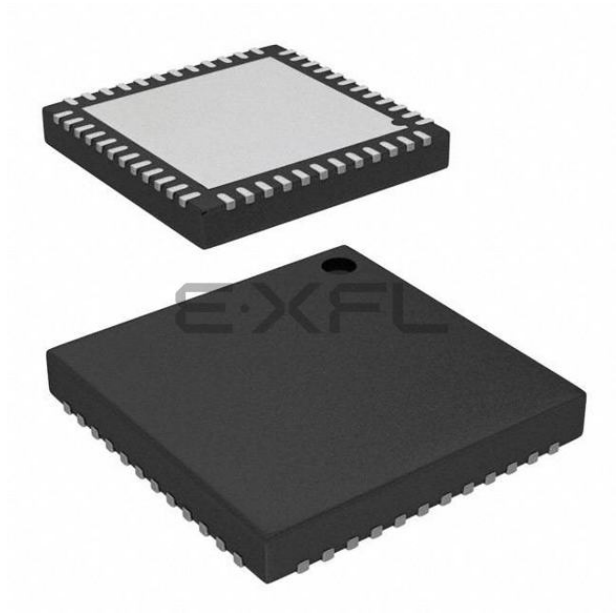

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Embedded - Microcontrollers - Application Specific: Tailored Solutions for Precision and Performance

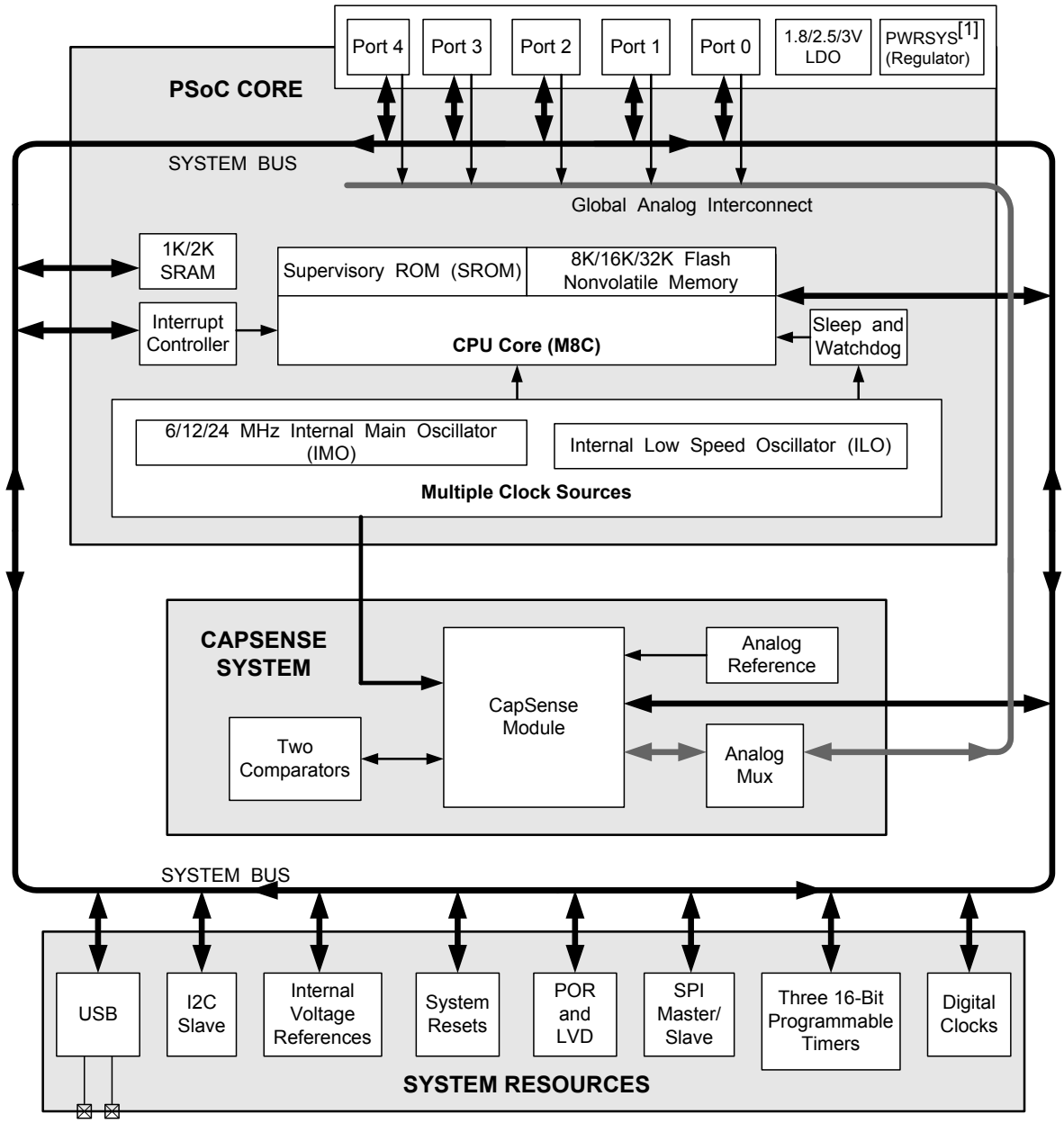
Embedded - Microcontrollers - Application Specific represents a category of microcontrollers designed with unique features and capabilities tailored to specific application needs. Unlike general-purpose microcontrollers, application-specific microcontrollers are optimized for particular tasks, offering enhanced performance, efficiency, and functionality to meet the demands of specialized applications.

What Are Embedded - Microcontrollers - Application Specific?

Application-specific microcontrollers are engineered to

Details	
Product Status	Obsolete
Applications	Capacitive Sensing
Core Processor	M8C
Program Memory Type	FLASH (8kB)
Controller Series	CY8C20xx6A
RAM Size	1K x 8
Interface	I²C, SPI
Number of I/O	36
Voltage - Supply	1.71V ~ 5.5V
Operating Temperature	-40°C ~ 85°C
Mounting Type	Surface Mount
Package / Case	48-VFQFN Exposed Pad
Supplier Device Package	48-QFN (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c20636an-24ltxi

Logic Block Diagram



Note
1. Internal voltage regulator for internal circuitry

More Information

Cypress provides a wealth of data at www.cypress.com to help you to select the right PSoC device for your design, and to help you to quickly and effectively integrate the device into your design. For a comprehensive list of resources, see the knowledge base article KBA92181, Resources Available for CapSense® Controllers. Following is an abbreviated list for CapSense devices:

- Overview: CapSense Portfolio, CapSense Roadmap
- Product Selectors: CapSense, CapSense Plus, CapSense Express, PSoC3 with CapSense, PSoC5 with CapSense, PSoC4. In addition, PSoC Designer offers a device selection tool at the time of creating a new project.
- Application notes: Cypress offers CapSense application notes covering a broad range of topics, from basic to advanced level. Recommended application notes for getting started with CapSense are:
  - AN64846: Getting Started With CapSense
  - AN73034: CY8C20xx6A/H/AS CapSense® Design Guide
  - AN2397: CapSense® Data Viewing Tools
- Technical Reference Manual (TRM):
  - PSoC® CY8C20xx6A/AS/L Family Technical Reference Manual
- Development Kits:
  - CY3280-20x66 Universal CapSense Controller Kit features a predefined control circuitry and plug-in hardware to make prototyping and debugging easy. Programming and I2C-to-USB Bridge hardware are included for tuning and data acquisition.
  - CY3280-BMM Matrix Button Module Kit consists of eight CapSense sensors organized in a 4x4 matrix format to form 16 physical buttons and eight LEDs. This module connects to any CY3280 Universal CapSense Controller Board, including CY3280-20x66 Universal CapSense Controller.
  - CY3280-BSM Simple Button Module Kit consists of ten CapSense buttons and ten LEDs. This module connects to any CY3280 Universal CapSense Controller Board, including CY3280-20x66 Universal CapSense Controller.

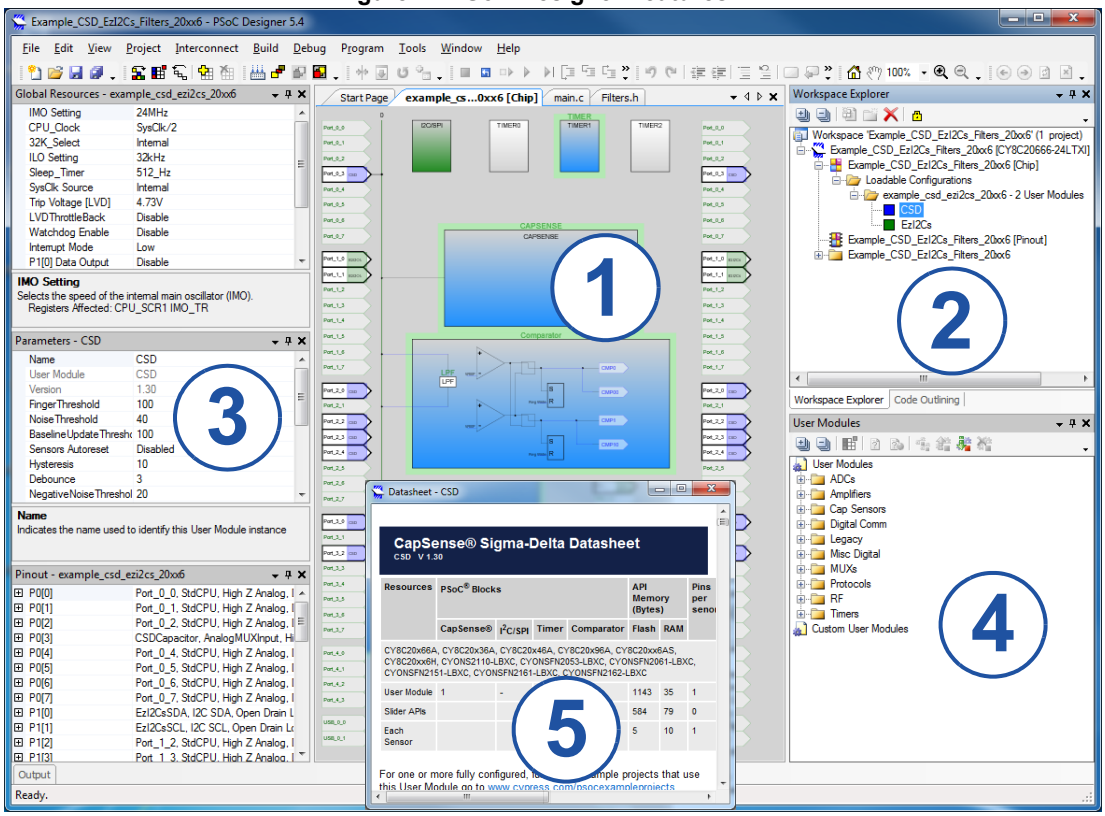
The CY3217-MiniProg1 and CY8CKIT-002 PSoC® MiniProg3 device provides an interface for flash programming.

PSoC Designer

PSoC Designer is a free Windows-based Integrated Design Environment (IDE). It enables concurrent hardware and firmware design of systems based on CapSense (see Figure 1). With PSoC Designer, you can:

1. Drag and drop User Modules to build your hardware system design in the main design workspace
2. Codesign your application firmware with the PSoC hardware, using the PSoC Designer IDE C compiler
3. Configure User Module
4. Explore the library of user modules
5. Review user module datasheets

Figure 1. PSoC Designer Features



Development Tools

PSoC Designer™ is the revolutionary integrated design environment (IDE) that you can use to customize PSoC to meet your specific application requirements. PSoC Designer software accelerates system design and time to market. Develop your applications using a library of precharacterized analog and digital peripherals (called user modules) in a drag-and-drop design environment. Then, customize your design by leveraging the dynamically generated application programming interface (API) libraries of code. Finally, debug and test your designs with the integrated debug environment, including in-circuit emulation and standard software debug features. PSoC Designer includes:

- Application editor graphical user interface (GUI) for device and user module configuration and dynamic reconfiguration
- Extensive user module catalog
- Integrated source-code editor (C and assembly)
- Free C compiler with no size restrictions or time limits
- Built-in debugger
- In-circuit emulation
- Built-in support for communication interfaces:
  - Hardware and software I^2C slaves and masters
  - Full-speed USB 2.0
  - Up to four full-duplex universal asynchronous receiver/transmitters (UARTs), SPI master and slave, and wireless

PSoC Designer supports the entire library of PSoC 1 devices and runs on Windows XP, Windows Vista, and Windows 7.

PSoC Designer Software Subsystems

Design Entry

In the chip-level view, choose a base device to work with. Then select different onboard analog and digital components that use the PSoC blocks, which are called user modules. Examples of user modules are analog-to-digital converters (ADCs), digital-to-analog converters (DACs), amplifiers, and filters. Configure the user modules for your chosen application and connect them to each other and to the proper pins. Then generate your project. This prepopulates your project with APIs and libraries that you can use to program your application.

The tool also supports easy development of multiple configurations and dynamic reconfiguration. Dynamic reconfiguration makes it possible to change configurations at run time. In essence, this lets you to use more than 100 percent of PSoC's resources for an application.

Code Generation Tools

The code generation tools work seamlessly within the PSoC Designer interface and have been tested with a full range of debugging tools. You can develop your design in C, assembly, or a combination of the two.

Assemblers. The assemblers allow you to merge assembly code seamlessly with C code. Link libraries automatically use absolute addressing or are compiled in relative mode, and linked with other software modules to get absolute addressing.

C Language Compilers. C language compilers are available that support the PSoC family of devices. The products allow you to create complete C programs for the PSoC family devices. The optimizing C compilers provide all of the features of C, tailored to the PSoC architecture. They come complete with embedded libraries providing port and bus operations, standard keypad and display support, and extended math functionality.

Debugger

PSoC Designer has a debug environment that provides hardware in-circuit emulation, allowing you to test the program in a physical system while providing an internal view of the PSoC device. Debugger commands allow you to read and program and read and write data memory, and read and write I/O registers. You can read and write CPU registers, set and clear breakpoints, and provide program run, halt, and step control. The debugger also lets you to create a trace buffer of registers and memory locations of interest.

Online Help System

The online help system displays online, context-sensitive help. Designed for procedural and quick reference, each functional subsystem has its own context-sensitive help. This system also provides tutorials and links to FAQs and an Online Support Forum to aid the designer.

In-Circuit Emulator

A low-cost, high-functionality in-circuit emulator (ICE) is available for development support. This hardware can program single devices.

The emulator consists of a base unit that connects to the PC using a USB port. The base unit is universal and operates with all PSoC devices. Emulation pods for each device family are available separately. The emulation pod takes the place of the PSoC device in the target board and performs full-speed (24 MHz) operation.

Pinouts

The CY8C20XX6A/S PSoC device is available in a variety of packages, which are listed and illustrated in the following tables. Every port pin (labeled with a “P”) is capable of Digital I/O and connection to the common analog bus. However, V_{SS}, V_{DD}, and XRES are not capable of Digital I/O.

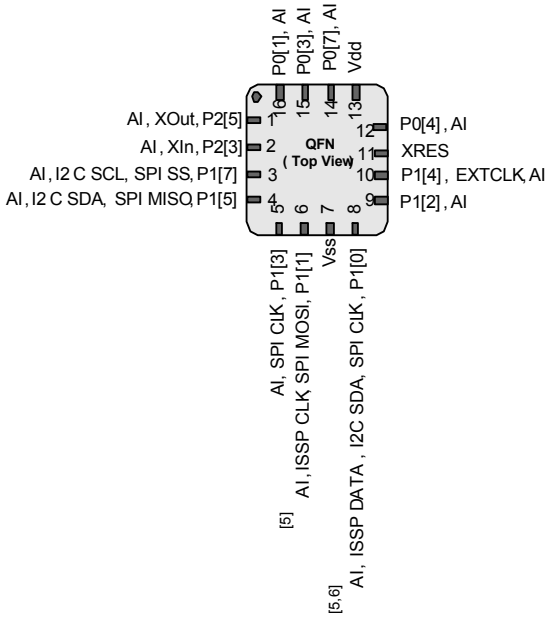
16-pin QFN (10 Sensing Inputs)[3, 4]

Table 1. Pin Definitions – CY8C20236A, CY8C20246A, CY8C20246AS PSoC Device

Pin No.	Type		Name	Description
	Digital	Analog		
1	I/O	I	P2[5]	Crystal output (XOut)
2	I/O	I	P2[3]	Crystal input (XIn)
3	IOHR	I	P1[7]	I^2C SCL, SPI SS
4	IOHR	I	P1[5]	I^2C SDA, SPI MISO
5	IOHR	I	P1[3]	SPI CLK
6	IOHR	I	P1[1]	ISSP CLK[5], I^2C SCL, SPI MOSI
7	Power		V_{SS}	Ground connection[7]
8	IOHR	I	P1[0]	ISSP DATA[5], I^2C SDA, SPI CLK[6]
9	IOHR	I	P1[2]	
10	IOHR	I	P1[4]	Optional external clock (EXTCLK)
11	Input		XRES	Active high external reset with internal pull-down
12	IOH	I	P0[4]	
13	Power		V_{DD}	Supply voltage
14	IOH	I	P0[7]	
15	IOH	I	P0[3]	Integrating input
16	IOH	I	P0[1]	Integrating input

LEGEND A = Analog, I = Input, O = Output, OH = 5 mA High Output Drive, R = Regulated Output.

Figure 3. CY8C20236A, CY8C20246A, CY8C20246AS



Notes
3. 13 GPIOs = 10 pins for capacitive sensing + 2 pins for I2C + 1 pin for modulation capacitor.
4. No Center Pad.
5. On power-up, the SDA(P1[0]) drives a strong high for 256 sleep clock cycles and drives resistive low for the next 256 sleep clock cycles. The SCL(P1[1]) line drives resistive low for 512 sleep clock cycles and both the pins transition to high impedance state. On reset, after XRES de-asserts, the SDA and the SCL lines drive resistive low for 8 sleep clock cycles and transition to high impedance state. Hence, during power-up or reset event, P1[1] and P1[0] may disturb the I2C bus. Use alternate pins if you encounter issues.
6. Alternate SPI clock.
7. All VSS pins should be brought out to one common GND plane.

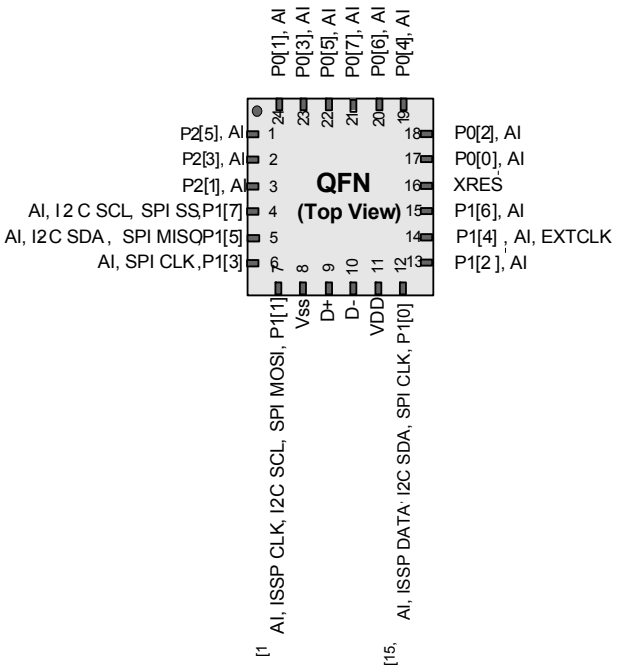
24-pin QFN (15 Sensing Inputs (With USB)) [13]

Table 3. Pin Definitions – CY8C20396A [14]

Pin No.	Type		Name	Description
	Digital	Analog		
1	I/O	I	P2[5]	
2	I/O	I	P2[3]	
3	I/O	I	P2[1]	
4	IOHR	I	P1[7]	I^2C SCL, SPI SS
5	IOHR	I	P1[5]	I^2C SDA, SPI MISO
6	IOHR	I	P1[3]	SPI CLK
7	IOHR	I	P1[1]	ISSP CLK[15], I^2C SCL, SPI MOSI
8	Power		V_{SS}	Ground[17]
9	I/O	I	D+	USB D+
10	I/O	I	D-	USB D-
11	Power		V_{DD}	Supply
12	IOHR	I	P1[0]	ISSP DATA[15], I^2C SDA, SPI CLK[16]
13	IOHR	I	P1[2]	
14	IOHR	I	P1[4]	Optional external clock input (EXTCLK)
15	IOHR	I	P1[6]	
16	RESET INPUT		XRES	Active high external reset with internal pull-down
17	IOH	I	P0[0]	
18	IOH	I	P0[2]	
19	IOH	I	P0[4]	
20	IOH	I	P0[6]	
21	IOH	I	P0[7]	
22	IOH	I	P0[5]	
23	IOH	I	P0[3]	Integrating input
24	IOH	I	P0[1]	Integrating input
CP	Power		V_{SS}	Center pad must be connected to Ground

LEGEND I = Input, O = Output, OH = 5 mA High Output Drive, R = Regulated Output

Figure 5. CY8C20396A



Notes
13. 20 GPIOs = 15 pins for capacitive sensing + 2 pins for I2C + 2 pins for USB + 1 pin for modulation capacitor.
14. The center pad (CP) on the QFN package must be connected to ground (V_{SS}) for best mechanical, thermal, and electrical performance. If not connected to ground, it must be electrically floated and not connected to any other signal.
15. On power-up, the SDA(P1[0]) drives a strong high for 256 sleep clock cycles and drives resistive low for the next 256 sleep clock cycles. The SCL(P1[1]) line drives resistive low for 512 sleep clock cycles and both the pins transition to high impedance state. On reset, after XRES de-asserts, the SDA and the SCL lines drive resistive low for 8 sleep clock cycles and transition to high impedance state. Hence, during power-up or reset event, P1[1] and P1[0] may disturb the I2C bus. Use alternate pins if you encounter issues.
16. Alternate SPI clock.
17. All VSS pins should be brought out to one common GND plane.

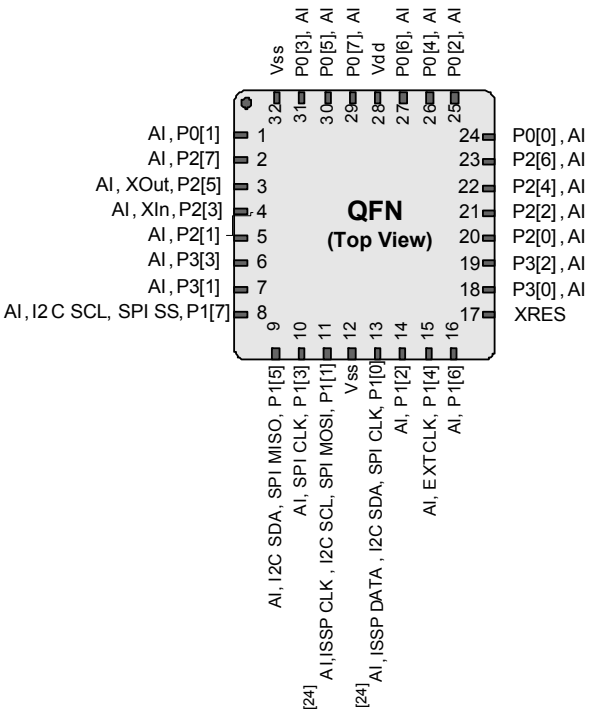
32-pin QFN (25 Sensing Inputs) [22]

Table 5. Pin Definitions – CY8C20436A, CY8C20446A, CY8C20446AS, CY8C20466A, CY8C20466AS[23]

Pin No.	Type		Name	Description
	Digital	Analog		
1	IOH	I	P0[1]	Integrating input
2	I/O	I	P2[7]	
3	I/O	I	P2[5]	Crystal output (XOut)
4	I/O	I	P2[3]	Crystal input (XIn)
5	I/O	I	P2[1]	
6	I/O	I	P3[3]	
7	I/O	I	P3[1]	
8	IOHR	I	P1[7]	I^2C SCL, SPI SS
9	IOHR	I	P1[5]	I^2C SDA, SPI MISO
10	IOHR	I	P1[3]	SPI CLK.
11	IOHR	I	P1[1]	ISSP CLK[24], I^2C SCL, SPI MOSI.
12	Power		V_{SS}	Ground connection[26]
13	IOHR	I	P1[0]	ISSP DATA[24], I^2C SDA, SPI CLK[25]
14	IOHR	I	P1[2]	
15	IOHR	I	P1[4]	Optional external clock input (EXTCLK)
16	IOHR	I	P1[6]	
17	Input		XRES	Active high external reset with internal pull-down
18	I/O	I	P3[0]	
19	I/O	I	P3[2]	
20	I/O	I	P2[0]	
21	I/O	I	P2[2]	
22	I/O	I	P2[4]	
23	I/O	I	P2[6]	
24	IOH	I	P0[0]	
25	IOH	I	P0[2]	
26	IOH	I	P0[4]	
27	IOH	I	P0[6]	
28	Power		V_{DD}	Supply voltage
29	IOH	I	P0[7]	
30	IOH	I	P0[5]	
31	IOH	I	P0[3]	Integrating input
32	Power		V_{SS}	Ground connection[26]
CP	Power		V_{SS}	Center pad must be connected to ground

LEGEND A = Analog, I = Input, O = Output, OH = 5 mA High Output Drive, R = Regulated Output.

Figure 7. CY8C20436A, CY8C20446A, CY8C20446AS, CY8C20466A, CY8C20466AS



Notes

22. 28 GPIOs = 25 pins for capacitive sensing + 2 pins for I2C + 1 pin for modulation capacitor.
23. The center pad (CP) on the QFN package must be connected to ground (V_{SS}) for best mechanical, thermal, and electrical performance. If not connected to ground, it must be electrically floated and not connected to any other signal.
24. On power-up, the SDA(P1[0]) drives a strong high for 256 sleep clock cycles and drives resistive low for the next 256 sleep clock cycles. The SCL(P1[1]) line drives resistive low for 512 sleep clock cycles and both the pins transition to high impedance state. On reset, after XRES de-asserts, the SDA and the SCL lines drive resistive low for 8 sleep clock cycles and transition to high impedance state. Hence, during power-up or reset event, P1[1] and P1[0] may disturb the I2C bus. Use alternate pins if you encounter issues.
25. Alternate SPI clock.
26. All VSS pins should be brought out to one common GND plane.

DC Chip-Level Specifications

Table 13 lists guaranteed maximum and minimum specifications for the entire voltage and temperature ranges.

Table 13. DC Chip-Level Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
V_{DD}[54, 55, 56, 57]	Supply voltage	No USB activity. Refer the table "DC POR and LVD Specifications" on page 26	1.71	–	5.50	V
V_{DDUSB}[54, 55, 56, 57]	Operating voltage	USB activity, USB regulator enabled	4.35	–	5.25	V
		USB activity, USB regulator bypassed	3.15	3.3	3.60	V
I_{DD24}	Supply current, IMO = 24 MHz	Conditions are $V_{DD} \leq 3.0$ V, $T_A = 25$ °C, CPU = 24 MHz. CapSense running at 12 MHz, no I/O sourcing current	–	2.88	4.00	mA
I_{DD12}	Supply current, IMO = 12 MHz	Conditions are $V_{DD} \leq 3.0$ V, $T_A = 25$ °C, CPU = 12 MHz. CapSense running at 12 MHz, no I/O sourcing current	–	1.71	2.60	mA
I_{DD6}	Supply current, IMO = 6 MHz	Conditions are $V_{DD} \leq 3.0$ V, $T_A = 25$ °C, CPU = 6 MHz. CapSense running at 6 MHz, no I/O sourcing current	–	1.16	1.80	mA
$I_{DDAVG10}$	Average supply current per sensor	One sensor scanned at 10 mS rate	–	250	–	µA
$I_{DDAVG100}$	Average supply current per sensor	One sensor scanned at 100 mS rate	–	25	–	µA
$I_{DDAVG500}$	Average supply current per sensor	One sensor scanned at 500 mS rate	–	7	–	µA
I_{SB0}[58, 59, 60, 61, 62, 63]	Deep sleep current	$V_{DD} \leq 3.0$ V, $T_A = 25$ °C, I/O regulator turned off	–	0.10	1.05	µA
I_{SB1}[58, 59, 60, 61, 62, 63]	Standby current with POR, LVD and sleep timer	$V_{DD} \leq 3.0$ V, $T_A = 25$ °C, I/O regulator turned off	–	1.07	1.50	µA
I_{SBI2C}[58, 59, 60, 61, 62, 63]	Standby current with I^2C enabled	Conditions are $V_{DD} = 3.3$ V, $T_A = 25$ °C and CPU = 24 MHz	–	1.64	–	µA

Notes

54. When V_{DD} remains in the range from 1.71 V to 1.9 V for more than 50 µs, the slew rate when moving from the 1.71 V to 1.9 V range to greater than 2 V must be slower than 1 V/500 µs to avoid triggering POR. The only other restriction on slew rates for any other voltage range or transition is the SR_{POWER_UP} parameter.
55. If powering down in standby sleep mode, to properly detect and recover from a V_{DD} brown out condition any of the following actions must be taken:
    a. Bring the device out of sleep before powering down.
    b. Assure that V_{DD} falls below 100 mV before powering back up.
    c. Set the No Buzz bit in the OSC_CR0 register to keep the voltage monitoring circuit powered during sleep.
    d. Increase the buzz rate to assure that the falling edge of V_{DD} is captured. The rate is configured through the PSSDC bits in the SLP_CFG register.
    For the referenced registers, refer to the *CY8C20X36 Technical Reference Manual*. In deep sleep mode, additional low power voltage monitoring circuitry allows V_{DD} brown out conditions to be detected for edge rates slower than 1V/ms.
56. For USB mode, the V_{DD} supply for bus-powered application should be limited to 4.35 V–5.35 V. For self-powered application, V_{DD} should be 3.15 V–3.45 V.
57. For proper CapSense block functionality, if the drop in V_{DD} exceeds 5% of the base V_{DD}, the rate at which V_{DD} drops should not exceed 200 mV/s. Base V_{DD} can be between 1.8 V and 5.5 V.
58. Errata: When the device is put to sleep in Standby or I2C_USB Mode and the bandgap circuit is refreshed less frequently than every 8 ms (default), the device may not come out of sleep when a sleep-ending input is received. For more information, see the "Errata" on page 46.
59. Errata: The I2C block exhibits occasional data and bus corruption errors when the I2C master initiates transactions while the device is in or out of transition of sleep mode. For more information, see the "Errata" on page 46.
60. Errata: When programmable timer 0 is used in "one-shot" mode by setting bit 1 of register 0,B0h (PT0_CFG), and the timer interrupt is used to wake the device from sleep, the interrupt service routine (ISR) may be executed twice. For more information, see the "Errata" on page 47.
61. Errata: When in sleep mode, if a GPIO interrupt happens simultaneously with a Timer0 or Sleep Timer interrupt, the GPIO interrupt may be missed, and the corresponding GPIO ISR not run. For more information, see the "Errata" on page 47.
62. Errata: If an interrupt is posted a short time (within 2.5 CPU cycles) before firmware commands the device to sleep, the interrupt will be missed. For more information, see the "Errata" on page 48.
63. Errata: Device wakes up from sleep when an analog interrupt is trigger. For more information, see the "Errata" on page 48.

DC GPIO Specifications

The following tables list guaranteed maximum and minimum specifications for the voltage and temperature ranges: 3.0 V to 5.5 V and –40 °C ≤ T_A ≤ 85 °C, 2.4 V to 3.0 V and –40 °C ≤ T_A ≤ 85 °C, or 1.71 V to 2.4 V and –40 °C ≤ T_A ≤ 85 °C, respectively. Typical parameters apply to 5 V and 3.3 V at 25 C and are for design guidance only.

Table 14. 3.0 V to 5.5 V DC GPIO Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
R_{PU}	Pull-up resistor	–	4	5.60	8	kΩ
V_{OH1}	High output voltage Port 2 or 3 or 4 pins	I_{OH} ≤ 10 µA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.20	–	–	V
V_{OH2}	High output voltage Port 2 or 3 or 4 pins	I_{OH} = 1 mA, maximum of 20 mA source current in all I/Os	V_{DD} – 0.90	–	–	V
V_{OH3}	High output voltage Port 0 or 1 pins with LDO regulator Disabled for port 1	I_{OH} < 10 µA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.20	–	–	V
V_{OH4}	High output voltage Port 0 or 1 pins with LDO regulator Disabled for port 1	I_{OH} = 5 mA, maximum of 20 mA source current in all I/Os	V_{DD} – 0.90	–	–	V
V_{OH5}	High output voltage Port 1 Pins with LDO Regulator Enabled for 3 V out	I_{OH} < 10 µA, V_{DD} > 3.1 V, maximum of 4 I/Os all sourcing 5 mA	2.85	3.00	3.30	V
V_{OH6}	High output voltage Port 1 pins with LDO regulator enabled for 3 V out	I_{OH} = 5 mA, V_{DD} > 3.1 V, maximum of 20 mA source current in all I/Os	2.20	–	–	V
V_{OH7}	High output voltage Port 1 pins with LDO enabled for 2.5 V out	I_{OH} < 10 µA, V_{DD} > 2.7 V, maximum of 20 mA source current in all I/Os	2.35	2.50	2.75	V
V_{OH8}	High output voltage Port 1 pins with LDO enabled for 2.5 V out	I_{OH} = 2 mA, V_{DD} > 2.7 V, maximum of 20 mA source current in all I/Os	1.90	–	–	V
V_{OH9}	High output voltage Port 1 pins with LDO enabled for 1.8 V out	I_{OH} < 10 µA, V_{DD} > 2.7 V, maximum of 20 mA source current in all I/Os	1.60	1.80	2.10	V
V_{OH10}	High output voltage Port 1 pins with LDO enabled for 1.8 V out	I_{OH} = 1 mA, V_{DD} > 2.7 V, maximum of 20 mA source current in all I/Os	1.20	–	–	V
V_{OL}	Low output voltage	I_{OL} = 25 mA, V_{DD} > 3.3 V, maximum of 60 mA sink current on even port pins (for example, P0[2] and P1[4]) and 60 mA sink current on odd port pins (for example, P0[3] and P1[5])	–	–	0.75	V
V_{IL}	Input low voltage	–	–	–	0.80	V
V_{IH}	Input high voltage	–	2.00	–	–	V
V_H	Input hysteresis voltage	–	–	80	–	mV
I_{IL}	Input leakage (Absolute Value)	–	–	0.001	1	µA
C_{PIN}	Pin capacitance	Package and pin dependent Temp = 25 °C	0.50	1.70	7	pF
$V_{ILLVT3.3}$	Input Low Voltage with low threshold enable set, Enable for Port1	Bit3 of IO_CFG1 set to enable low threshold voltage of Port1 input	0.8	V	–	–
$V_{IHLVT3.3}$	Input High Voltage with low threshold enable set, Enable for Port1	Bit3 of IO_CFG1 set to enable low threshold voltage of Port1 input	1.4	–	–	V
$V_{ILLVT5.5}$	Input Low Voltage with low threshold enable set, Enable for Port1	Bit3 of IO_CFG1 set to enable low threshold voltage of Port1 input	0.8	V	–	–
$V_{IHLVT5.5}$	Input High Voltage with low threshold enable set, Enable for Port1	Bit3 of IO_CFG1 set to enable low threshold voltage of Port1 input	1.7	–	–	V

Table 15. 2.4 V to 3.0 V DC GPIO Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
R_{PU}	Pull-up resistor	–	4	5.60	8	kΩ
V_{OH1}	High output voltage Port 2 or 3 or 4 pins	I_{OH} < 10 µA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.20	–	–	V
V_{OH2}	High output voltage Port 2 or 3 or 4 pins	I_{OH} = 0.2 mA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.40	–	–	V
V_{OH3}	High output voltage Port 0 or 1 pins with LDO regulator Disabled for port 1	I_{OH} < 10 µA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.20	–	–	V
V_{OH4}	High output voltage Port 0 or 1 pins with LDO regulator Disabled for Port 1	I_{OH} = 2 mA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.50	–	–	V
V_{OH5A}	High output voltage Port 1 pins with LDO enabled for 1.8 V out	I_{OH} < 10 µA, V_{DD} > 2.4 V, maximum of 20 mA source current in all I/Os	1.50	1.80	2.10	V
V_{OH6A}	High output voltage Port 1 pins with LDO enabled for 1.8 V out	I_{OH} = 1 mA, V_{DD} > 2.4 V, maximum of 20 mA source current in all I/Os	1.20	–	–	V
V_{OL}	Low output voltage	IOL = 10 mA, maximum of 30 mA sink current on even port pins (for example, P0[2] and P1[4]) and 30 mA sink current on odd port pins (for example, P0[3] and P1[5])	–	–	0.75	V
V_{IL}	Input low voltage	–	–	–	0.72	V
V_{IH}	Input high voltage	–	1.40	–		V
V_H	Input hysteresis voltage	–	–	80	–	mV
I_{IL}	Input leakage (absolute value)	–	–	1	1000	nA
C_{PIN}	Capacitive load on pins	Package and pin dependent Temp = 25 °C	0.50	1.70	7	pF
$V_{ILLVT2.5}$	Input Low Voltage with low threshold enable set, Enable for Port1	Bit3 of IO_CFG1 set to enable low threshold voltage of Port1 input	0.7	V	–	
$V_{IHLVT2.5}$	Input High Voltage with low threshold enable set, Enable for Port1	Bit3 of IO_CFG1 set to enable low threshold voltage of Port1 input	1.2		–	V

Table 16. 1.71 V to 2.4 V DC GPIO Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
R_{PU}	Pull-up resistor	–	4	5.60	8	kΩ
V_{OH1}	High output voltage Port 2 or 3 or 4 pins	I_{OH} = 10 µA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.20	–	–	V
V_{OH2}	High output voltage Port 2 or 3 or 4 pins	I_{OH} = 0.5 mA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.50	–	–	V
V_{OH3}	High output voltage Port 0 or 1 pins with LDO regulator Disabled for Port 1	I_{OH} = 100 µA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.20	–	–	V
V_{OH4}	High output voltage Port 0 or 1 Pins with LDO Regulator Disabled for Port 1	I_{OH} = 2 mA, maximum of 10 mA source current in all I/Os	V_{DD} – 0.50	–	–	V
V_{OL}	Low output voltage	I_{OL} = 5 mA, maximum of 20 mA sink current on even port pins (for example, P0[2] and P1[4]) and 30 mA sink current on odd port pins (for example, P0[3] and P1[5])	–	–	0.40	V
V_{IL}	Input low voltage	–	–	–	0.30 × V_{DD}	V

DC I²C Specifications

Table 24 list guaranteed maximum and minimum specifications for the voltage and temperature ranges: 3.0 V to 5.5 V and –40 °C ≤ T_A ≤ 85 °C, 2.4 V to 3.0 V and –40 °C ≤ T_A ≤ 85 °C, or 1.71 V to 2.4 V and –40 °C ≤ T_A ≤ 85 °C, respectively. Typical parameters apply to 5 V and 3.3 V at 25 °C and are for design guidance only.

Table 24. DC I²C Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
V_{ILI2C}	Input low level	3.1 V ≤ V_{DD} ≤ 5.5 V	–	–	0.25 × V_{DD}	V
		2.5 V ≤ V_{DD} ≤ 3.0 V	–	–	0.3 × V_{DD}	V
		1.71 V ≤ V_{DD} ≤ 2.4 V	–	–	0.3 × V_{DD}	V
V_{IHI2C}	Input high level	1.71 V ≤ V_{DD} ≤ 5.5 V	0.65 × V_{DD}	–	–	V

DC Reference Buffer Specifications

Table 25 list guaranteed maximum and minimum specifications for the voltage and temperature ranges: 3.0 V to 5.5 V and –40 °C ≤ T_A ≤ 85 °C, 2.4 V to 3.0 V and –40 °C ≤ T_A ≤ 85 °C, or 1.71 V to 2.4 V and –40 °C ≤ T_A ≤ 85 °C, respectively. Typical parameters apply to 5 V and 3.3 V at 25 °C and are for design guidance only.

Table 25. DC Reference Buffer Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
V_{Ref}	Reference buffer output	1.7 V ≤ V_{DD} ≤ 5.5 V	1	–	1.05	V
V_{RefHi}	Reference buffer output	1.7 V ≤ V_{DD} ≤ 5.5 V	1.2	–	1.25	V

DC IDAC Specifications

Table 26 lists guaranteed maximum and minimum specifications for the entire voltage and temperature ranges.

Table 26. DC IDAC Specifications

Symbol	Description	Min	Typ	Max	Units	Notes
IDAC_DNL	Differential nonlinearity	–4.5	–	+4.5	LSB	–
IDAC_INL	Integral nonlinearity	–5	–	+5	LSB	–
IDAC_Gain (Source)	Range = 0.5x	6.64	–	22.46	µA	DAC setting = 128 dec. Not recommended for CapSense applications.
	Range = 1x	14.5	–	47.8	µA	
	Range = 2x	42.7	–	92.3	µA	
	Range = 4x	91.1	–	170	µA	DAC setting = 128 dec
	Range = 8x	184.5	–	426.9	µA	DAC setting = 128 dec

AC Programming Specifications

Figure 15. AC Waveform

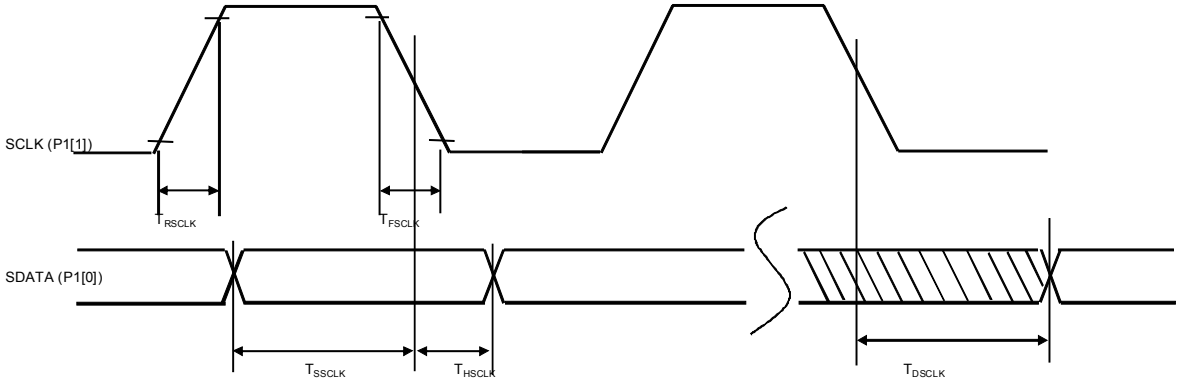


Table 33 lists the guaranteed maximum and minimum specifications for the entire voltage and temperature ranges.

Table 33. AC Programming Specifications

Symbol	Description	Conditions	Min	Typ	Max	Units
t_{RSCLK}	Rise time of SCLK	–	1	–	20	ns
t_{FSCLK}	Fall time of SCLK	–	1	–	20	ns
t_{SSCLK}	Data setup time to falling edge of SCLK	–	40	–	–	ns
t_{HSCLK}	Data hold time from falling edge of SCLK	–	40	–	–	ns
F_{SCLK}	Frequency of SCLK	–	0	–	8	MHz
t_{ERASEB}	Flash erase time (block)	–	–	–	18	ms
t_{WRITE}	Flash block write time	–	–	–	25	ms
t_{DSCLK}	Data out delay from falling edge of SCLK	$3.6 < V_{DD}$	–	–	60	ns
t_{DSCLK3}	Data out delay from falling edge of SCLK	$3.0 \le V_{DD} \le 3.6$	–	–	85	ns
t_{DSCLK2}	Data out delay from falling edge of SCLK	$1.71 \le V_{DD} \le 3.0$	–	–	130	ns
t_{XRST3}	External reset pulse width after power-up	Required to enter programming mode when coming out of sleep	300	–	–	µs
t_{XRES}	XRES pulse length	–	300	–	–	µs
$t_{VDDWAIT}$[71]	V_{DD} stable to wait-and-poll hold off	–	0.1	–	1	ms
$t_{VDDXRES}$[71]	V_{DD} stable to XRES assertion delay	–	14.27	–	–	ms
t_{POLL}	SDATA high pulse time	–	0.01	–	200	ms
t_{ACQ}[71]	“Key window” time after a V_{DD} ramp acquire event, based on 256 ILO clocks.	–	3.20	–	19.60	ms
$t_{XRESINI}$[71]	“Key window” time after an XRES event, based on 8 ILO clocks	–	98	–	615	µs

Note
71. Valid from 5 to 50 °C. See the spec, CY8C20X66, CY8C20X46, CY8C20X36, CY7C643XX, CY7C604XX, CY8CTST2XX, CY8CTMG2XX, CY8C20X67, CY8C20X47, CY8C20X37, Programming Spec for more details.

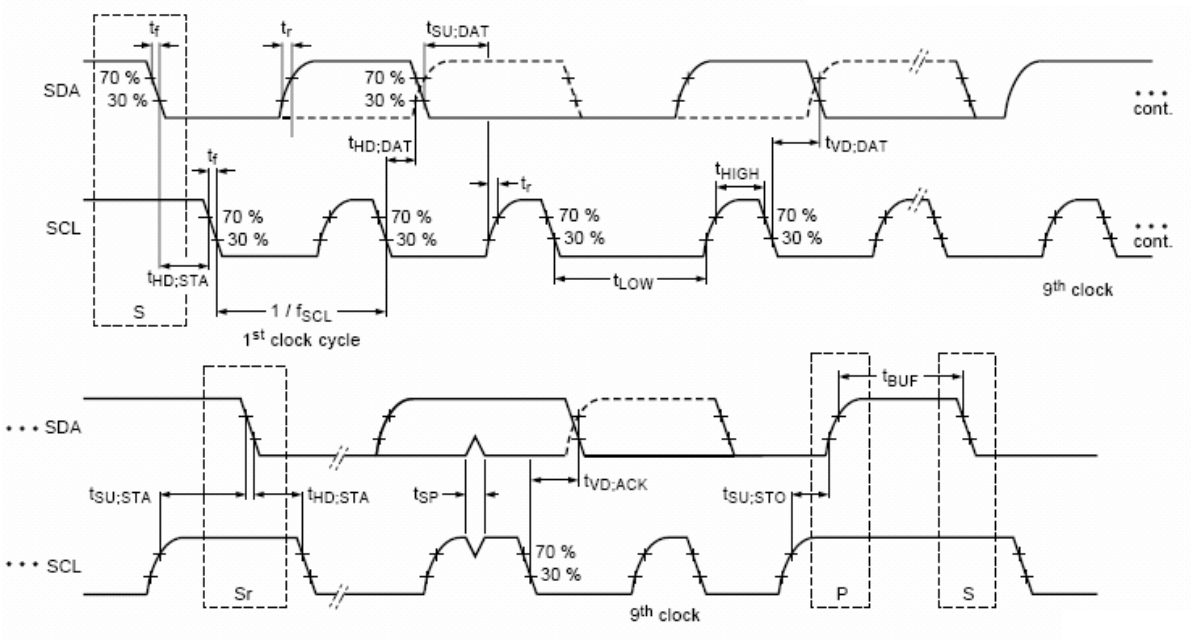
AC I²C Specifications

Table 34 lists guaranteed maximum and minimum specifications for the entire voltage and temperature ranges.

Table 34. AC Characteristics of the I²C SDA and SCL Pins

Symbol	Description	Standard Mode		Fast Mode		Units
		Min	Max	Min	Max	
f_{SCL}	SCL clock frequency	0	100	0	400	kHz
$t_{HD;STA}$	Hold time (repeated) START condition. After this period, the first clock pulse is generated	4.0	–	0.6	–	µs
t_{LOW}	LOW period of the SCL clock	4.7	–	1.3	–	µs
t_{HIGH}	HIGH Period of the SCL clock	4.0	–	0.6	–	µs
$t_{SU;STA}$	Setup time for a repeated START condition	4.7	–	0.6	–	µs
$t_{HD;DAT}$	Data hold time	0	3.45	0	0.90	µs
$t_{SU;DAT}$	Data setup time	250	–	100[72]	–	ns
$t_{SU;STO}$	Setup time for STOP condition	4.0	–	0.6	–	µs
t_{BUF}	Bus free time between a STOP and START condition	4.7	–	1.3	–	µs
t_{SP}	Pulse width of spikes are suppressed by the input filter	–	–	0	50	ns

Figure 16. Definition for Timing for Fast/Standard Mode on the I²C Bus



Note

72. A Fast-Mode I²C-bus device can be used in a standard mode I²C-bus system, but the requirement $t_{SU;DAT} \geq 250$ ns must then be met. This automatically be the case if the device does not stretch the LOW period of the SCL signal. If such device does stretch the LOW period of the SCL signal, it must output the next data bit to the SDA line $t_{rmax} + t_{SU;DAT} = 1000 + 250 = 1250$ ns (according to the Standard-Mode I²C-bus specification) before the SCL line is released.

Figure 23. 32-pin QFN (5 × 5 × 0.55 mm) LQ32 3.5 × 3.5 E-Pad (Sawn) Package Outline, 001-42168

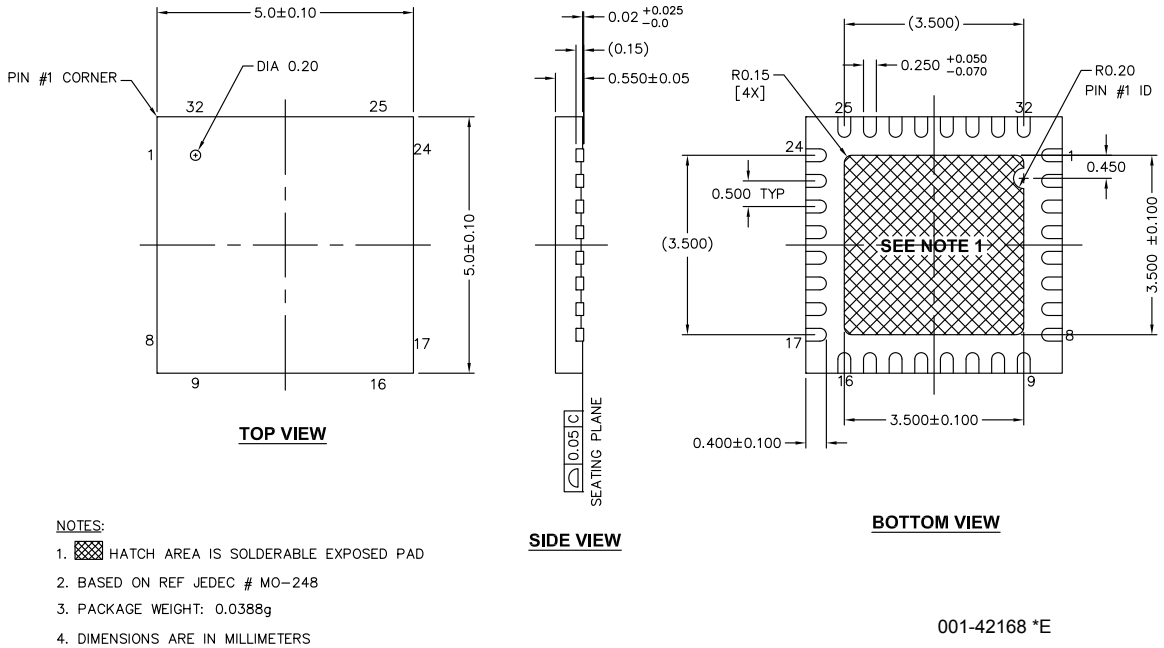


Figure 24. 48-pin SSOP (300 Mils) O483 Package Outline, 51-85061

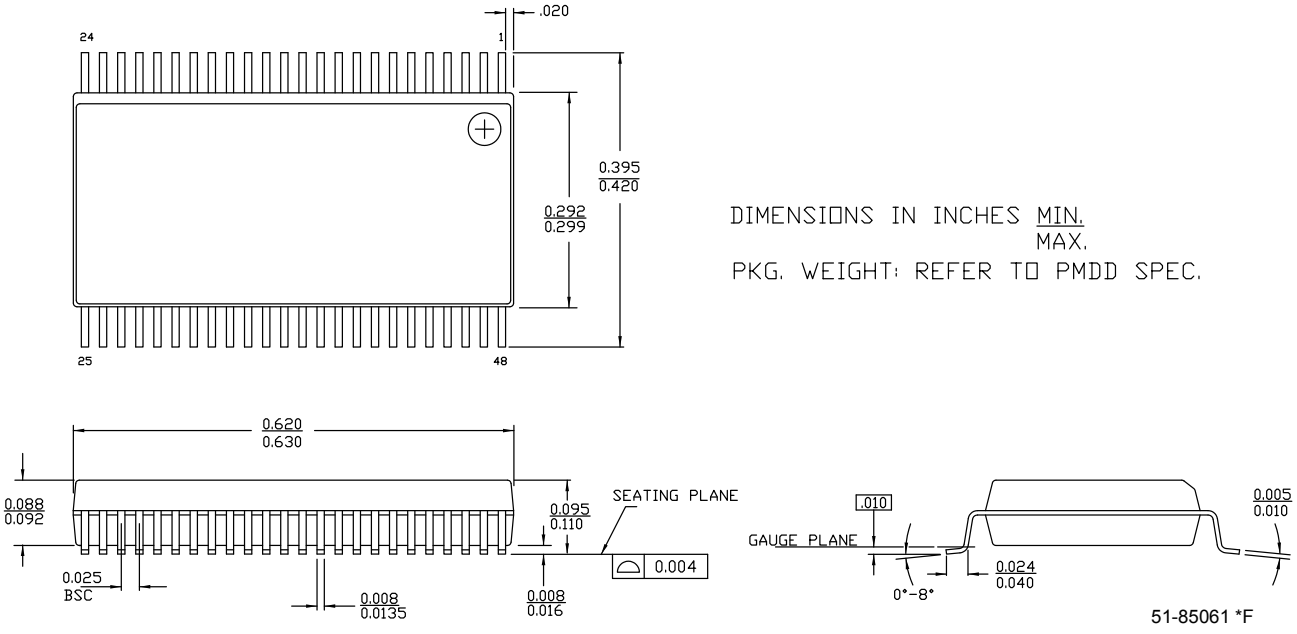
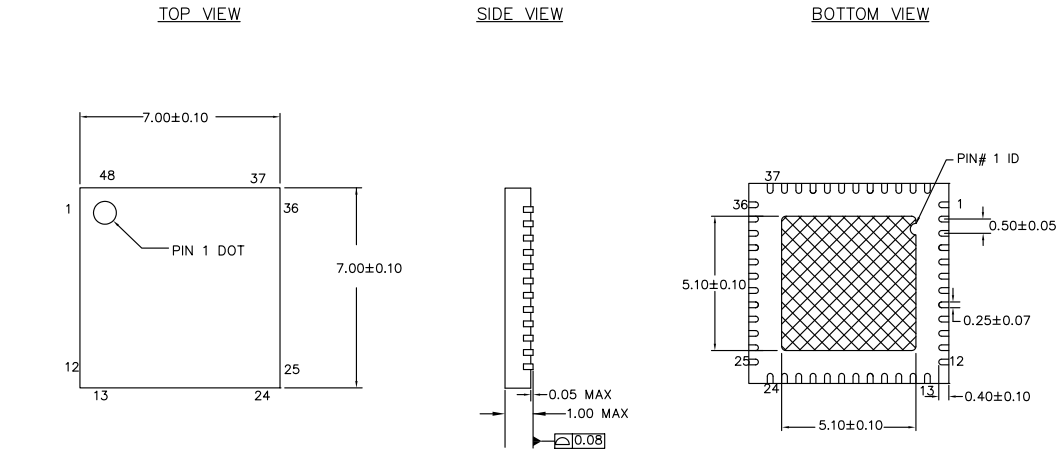


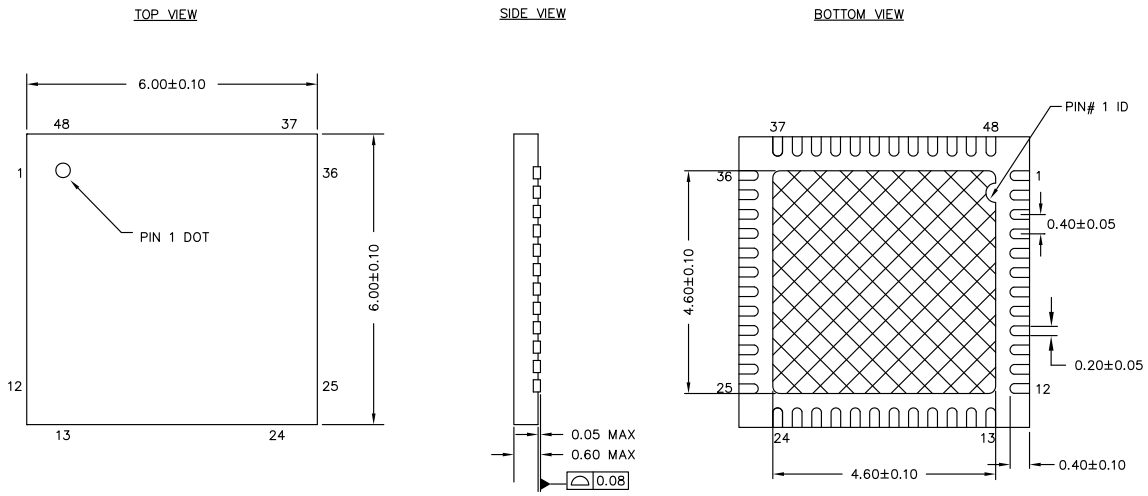
Figure 25. 48-pin QFN (7 × 7 × 1.0 mm) LT48A 5.1 × 5.1 E-Pad (Sawn) Package Outline, 001-13191



NOTES:
1. HATCH AREA IS SOLDERABLE EXPOSED METAL.
2. REFERENCE JEDEC#: MO−220
3. PACKAGE WEIGHT: 13 ± 1 mg
4. ALL DIMENSIONS ARE IN MILLIMETERS

001-13191 *H

Figure 26. 48-pin QFN (6 × 6 × 0.6 mm) LQ48A 4.6 × 4.6 E-Pad (Sawn) Package Outline, 001-57280



NOTES:
1. HATCH AREA IS SOLDERABLE EXPOSED PAD
2. REFERENCE JEDEC # MO−248
3. PACKAGE WEIGHT: 68 ±7 mg
4. ALL DIMENSIONS ARE IN MILLIMETERS

001-57280 *E

Important Notes

- For information on the preferred dimensions for mounting QFN packages, see the following Application Note at http://www.amkor.com/products/notes_papers/MLFAppNote.pdf.
- Pinned vias for thermal conduction are not required for the low power PSoC device.

Acronyms

Table 42. Acronyms Used in this Document

Acronym	Description
AC	alternating current
ADC	analog-to-digital converter
API	application programming interface
CMOS	complementary metal oxide semiconductor
CPU	central processing unit
DAC	digital-to-analog converter
DC	direct current
EOP	end of packet
FSR	full scale range
GPIO	general purpose input/output
GUI	graphical user interface
I^2C	inter-integrated circuit
ICE	in-circuit emulator
IDAC	digital analog converter current
ILO	internal low speed oscillator
IMO	internal main oscillator
I/O	input/output
ISSP	in-system serial programming
LCD	liquid crystal display
LDO	low dropout (regulator)
LSB	least-significant bit
LVD	low voltage detect
MCU	micro-controller unit
MIPS	mega instructions per second
MISO	master in slave out
MOSI	master out slave in
MSB	most-significant bit
OCD	on-chip debugger
POR	power on reset
PPOR	precision power on reset
PSRR	power supply rejection ratio
PWRSYS	power system
PSoC®	Programmable System-on-Chip
SLIMO	slow internal main oscillator
SRAM	static random access memory
SNR	signal to noise ratio
QFN	quad flat no-lead
SCL	serial I2C clock
SDA	serial I2C data
SDATA	serial ISSP data
SPI	serial peripheral interface
SS	slave select
SSOP	shrink small outline package
TC	test controller
USB	universal serial bus
USB D+	USB Data+
USB D–	USB Data–
WLCSP	wafer level chip scale package
XTAL	crystal

Reference Documents

- *Technical Reference Manual for CY8C20xx6 devices*
- *In-system Serial Programming (ISSP) protocol for 20xx6* (AN2026C)
- *Host Sourced Serial Programming for 20xx6 devices* (AN59389)

Document Conventions

Units of Measure

Table 43. Units of Measure

Symbol	Unit of Measure
°C	degree Celsius
dB	decibels
fF	femtofarad
g	gram
Hz	hertz
KB	1024 bytes
Kbit	1024 bits
KHz	kilohertz
Ksps	kilo samples per second
kΩ	kilohm
MHz	megahertz
MΩ	megaohm
µA	microampere
µF	microfarad
µH	microhenry
µs	microsecond
µW	microwatt
mA	milliampere
ms	millisecond
mV	millivolt
nA	nanoampere
nF	nanofarad
ns	nanosecond
nV	nanovolt
W	ohm
pA	picoampere
pF	picofarad
pp	peak-to-peak
ppm	parts per million
ps	picosecond
sps	samples per second
s	sigma: one standard deviation
V	volt
W	watt

Numeric Naming

Hexadecimal numbers are represented with all letters in uppercase with an appended lowercase ‘h’ (for example, ‘14h’ or ‘3Ah’). Hexadecimal numbers may also be represented by a ‘0x’ prefix, the C coding convention. Binary numbers have an appended lowercase ‘b’ (for example, 01010100b’ or ‘01000011b’). Numbers not indicated by an ‘h’, ‘b’, or 0x are decimal.

Glossary

Crosspoint connection	Connection between any GPIO combination via analog multiplexer bus.
Differential non-linearity	Ideally, any two adjacent digital codes correspond to output analog voltages that are exactly one LSB apart. Differential non-linearity is a measure of the worst case deviation from the ideal 1 LSB step.
Hold time	Hold time is the time following a clock event during which the data input to a latch or flip-flop must remain stable in order to guarantee that the latched data is correct.
I^2C	It is a serial multi-master bus used to connect low speed peripherals to MCU.
Integral nonlinearity	It is a term describing the maximum deviation between the ideal output of a DAC/ADC and the actual output level.
Latch-up current	Current at which the latch-up test is conducted according to JESD78 standard (at 125 degree Celsius)
Power supply rejection ratio (PSRR)	The PSRR is defined as the ratio of the change in supply voltage to the corresponding change in output voltage of the device.
Scan	The conversion of all sensor capacitances to digital values.
Setup time	Period required to prepare a device, machine, process, or system for it to be ready to function.
Signal-to-noise ratio	The ratio between a capacitive finger signal and system noise.
SPI	Serial peripheral interface is a synchronous serial data link standard.

Errata

This section describes the errata for the PSoC® CY8C20x36A/46A/66A/96A/46AS/66AS/36H/46H families. Details include errata trigger conditions, scope of impact, available workarounds, and silicon revision applicability. Contact your local Cypress Sales Representative if you have questions.

Qualification Status

Product Status: Production released.

Errata Summary

The following Errata items apply to CY8C20x36A/46A/66A/96A/46AS/66AS/36H/46H families.

1. Wakeup from sleep may intermittently fail

■ **Problem Definition**

When the device is put to sleep in Standby or I2C_USB Mode and the bandgap circuit is refreshed less frequently than every 8 ms (default), the device may not come out of sleep when a sleep-ending input is received.

■ **Parameters Affected**

None

■ **Trigger Condition(S)**

By default, when the device is in the Standby or I2C_USB sleep modes, the bandgap circuit is powered-up approximately every 8 ms to facilitate detection of POR or LVD events. This interval can be lengthened or the periodic power-up disabled to reduce sleep current by setting the ALT_BUZZ bits in the SLP_CFG2 register or the Disable Buzz bit in the OSC_CR0 register respectively. If the bandgap circuit refresh interval is set longer than the default 8 ms, the device may fail to wakeup from sleep and enter a locked up state that can only be recovered by Watchdog Reset, XRES, or POR.

■ **Scope of Impact**

The trigger conditions outlined above may cause the device to never wakeup.

■ **Workaround**

Prior to entering Standby or I2C_USB sleep modes, do not lengthen or disable the bandgap refresh interval by manipulating the ALT_BUZZ bits in the SLP_CFG2 register or the Disable Buzz bit in the OSC_CR0 register respectively.

■ **Fix Status**

This issue will not be corrected in the next silicon revision.

2. I^2C Errors

■ **Problem Definition**

The I^2C block exhibits occasional data and bus corruption errors when the I^2C master initiates transactions while the device is transitioning in to or out of sleep mode.

■ **Parameters Affected**

Affects reliability of I^2C communication to device, and between I^2C master and third party I^2C slaves.

■ **Trigger Condition(S)**

Triggered by transitions into and out of the device's sleep mode.

■ **Scope of Impact**

Data errors result in incorrect data reported to the I^2C master, or incorrect data received from the master by the device. Bus corruption errors can corrupt data in transactions between the I^2C master and third party I^2C slaves.

■ **Workaround**

Firmware workarounds are available in firmware. Generally the workaround consists of disconnecting the I^2C block from the bus prior to going to sleep modes. I^2C transactions during sleep are supported by a protocol in which the master wakes the device prior to the I^2C transaction.

■ **Fix Status**

To be fixed in future silicon.

■ **Changes**

None

3. DoubleTimer0 ISR

■ **Problem Definition**

When programmable timer 0 is used in “one-shot” mode by setting bit 1 of register 0,B0h (PT0_CFG), and the timer interrupt is used to wake the device from sleep, the interrupt service routine (ISR) may be executed twice.

■ **Parameters Affected**

No datasheet parameters are affected.

■ **Trigger Condition(S)**

Triggered by enabling one-shot mode in the timer, and using the timer to wake from sleep mode.

■ **Scope of Impact**

The ISR may be executed twice.

■ **Workaround**

In the ISR, firmware should clear the one-shot bit with a statement such as “`and reg[B0h], FDh`”

■ **Fix Status**

Will not be fixed

■ **Changes**

None

4. Missed GPIO Interrupt

■ **Problem Definition**

When in sleep mode, if a GPIO interrupt happens simultaneously with a Timer0 or Sleep Timer interrupt, the GPIO interrupt may be missed, and the corresponding GPIO ISR not run.

■ **Parameters Affected**

No datasheet parameters are affected.

■ **Trigger Condition(S)**

Triggered by enabling sleep mode, then having GPIO interrupt occur simultaneously with a Timer 0 or Sleep Timer interrupt.

■ **Scope of Impact**

The GPIO interrupt service routine will not be run.

■ **Workaround**

The system should be architected such that a missed GPIO interrupt may be detected. For example, if a GPIO is used to wake the system to perform some function, the system should detect if the function is not performed, and re-issue the GPIO interrupt.

Alternatively, if a GPIO interrupt is required to wake the system, then firmware should disable the Sleep Timer and Timer0.

Alternatively, the ISR’s for Sleep Timer and Timer0 should manually check the state of the GPIO to determine if the host system has attempted to generate a GPIO interrupt.

■ **Fix Status**

Will not be fixed

■ **Changes**

None

Document History Page *(continued)*

Document Title: CY8C20XX6A/S, 1.8 V Programmable CapSense® Controller with SmartSense™ Auto-tuning 1–33 Buttons, 0–6 Sliders Document Number: 001-54459				
Revision	**ECN**	**Orig. of Change**	**Submission Date**	**Description of Change**
*P	3774062	UBU	10/11/2012	Updated Electrical Specifications: Updated AC Chip-Level Specifications: Updated Table 27: Changed minimum value of F_{32K1} parameter from 19 kHz to 15 kHz. Updated Packaging Information: spec 001-09116 – Changed revision from *F to *G. spec 001-13937 – Changed revision from *D to *E. spec 51-85061 – Changed revision from *E to *F. spec 001-13191 – Changed revision from *F to *G. spec 001-57280 – Changed revision from *C to *D.
*Q	3807186	PKS	15/11/2012	No content update; appended to EROS document.
*R	3836626	SRLI	01/03/2013	Updated Document Title to read as “CY8C20XX6A/S, 1.8 V Programmable CapSense® Controller with SmartSense™ Auto-tuning 1–33 Buttons, 0–6 Sliders”. Updated Features. Updated PSoC® Functional Overview: Replaced “CY8C20X36A/46A/66A/96A/46AS/66AS” with “CY8C20XX6A/S”. Updated Getting Started: Replaced “CY8C20X36A/46A/66A/96A/46AS/66AS” with “CY8C20XX6A/S”. Updated Pinouts: Updated 16-pin QFN (10 Sensing Inputs)[3, 4]: Replaced “12 Sensing Inputs” with “10 Sensing Inputs” in heading, added Note 3 only. Updated 24-pin QFN (17 Sensing Inputs) [8]: Replaced “12 Sensing Inputs” with “17 Sensing Inputs” in heading, added Note 8 only. Updated 24-pin QFN (15 Sensing Inputs (With USB)) [13]: Replaced “18 Sensing Inputs” with “15 Sensing Inputs” in heading, added Note 13 only. Updated 30-ball WLCSP (24 Sensing Inputs) [18]: Replaced “26 Sensing Inputs” with “24 Sensing Inputs” in heading, added Note 18 only. Updated 32-pin QFN (25 Sensing Inputs) [22]: Replaced “27 Sensing Inputs” with “25 Sensing Inputs” in heading, added Note 22 only. updated 32-pin QFN (22 Sensing Inputs (With USB)) [27]: Replaced “24 Sensing Inputs” with “22 Sensing Inputs” in heading, added Note 27 only. Updated 48-pin SSOP (31 Sensing Inputs) [32]: Replaced “33 Sensing Inputs” with “31 Sensing Inputs” in heading, added Note 32 only. Updated 48-pin QFN (33 Sensing Inputs) [36]: Replaced “35 Sensing Inputs” with “33 Sensing Inputs” in heading, added Note 36 only. Updated 48-pin QFN (33 Sensing Inputs (With USB)) [41]: Replaced “35 Sensing Inputs” with “33 Sensing Inputs” in heading, added Note 41 only. Updated 48-pin QFN (OCD) (33 Sensing Inputs) [46]: Added “33 Sensing Inputs” in heading, added Note 46 only. Updated Packaging Information: spec 001-42168 – Changed revision from *D to *E. spec 001-57280 – Changed revision from *D to *E.
*S	3997568	BVI	05/11/2013	Added Errata.
*T	4044148	BVI	06/28/2013	Added Errata Footnotes. Updated Packaging Information: spec 001-09116 – Changed revision from *G to *H. Updated to new template.

Document History Page *(continued)*

Document Title: CY8C20XX6A/S, 1.8 V Programmable CapSense® Controller with SmartSense™ Auto-tuning 1–33 Buttons, 0–6 Sliders Document Number: 001-54459				
Revision	**ECN**	**Orig. of Change**	**Submission Date**	**Description of Change**
*U	4185313	BVI	11/07/2013	Updated Features. Updated Packaging Information: spec 001-09116 – Changed revision from *H to *I.
*V	4622119	SSHH	01/13/2015	Added More Information.
*W	4825924	SSHH	07/07/2015	Updated Pinouts: Updated 16-pin QFN (10 Sensing Inputs)[3, 4]: Updated Table 1: Added Note 7 and referred the same note in description of V_{SS} pin. Updated 24-pin QFN (17 Sensing Inputs) [8]: Updated Table 2: Added Note 12 and referred the same note in description of V_{SS} pin. Updated 24-pin QFN (15 Sensing Inputs (With USB)) [13]: Updated Table 3: Added Note 17 and referred the same note in description of V_{SS} pin. Updated 30-ball WLCSP (24 Sensing Inputs) [18]: Updated Table 4: Added Note 21 and referred the same note in description of V_{SS} pin. Updated 32-pin QFN (25 Sensing Inputs) [22]: Updated Table 5: Added Note 26 and referred the same note in description of V_{SS} pin. Updated 32-pin QFN (22 Sensing Inputs (With USB)) [27]: Updated Table 6: Added Note 31 and referred the same note in description of V_{SS} pin. Updated 48-pin SSOP (31 Sensing Inputs) [32]: Updated Table 7: Added Note 35 and referred the same note in description of V_{SS} pin. Updated 48-pin QFN (33 Sensing Inputs) [36]: Updated Table 8: Added Note 40 and referred the same note in description of V_{SS} pin. Updated 48-pin QFN (33 Sensing Inputs (With USB)) [41]: Updated Table 9: Added Note 45 and referred the same note in description of V_{SS} pin. Updated 48-pin QFN (OCD) (33 Sensing Inputs) [46]: Updated Table 10: Added Note 52 and referred the same note in description of V_{SS} pin. Updated Ordering Information: Removed prune part numbers (CY8C20636AN-24LTXI and CY8C20636AN-24LTXIT). Updated Packaging Information: spec 001-13937 – Changed revision from *E to *F. spec 001-13191 – Changed revision from *G to *H.
*X	5394582	SSHH	08/08/2016	Updated to new template. Completing Sunset Review.